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Spec No: 002-05232

Spec Title: AN205232 - FM3 MB9B506 Series IEC60730 Class B Self-Test Library

Replaced by: NONE

AN205232

FM3 MB9B506 Series IEC60730 Class B Self-Test Library

Associated Part Family: MB9B506 Series

MB9B506 series MCU is 32-bit general purpose MCU of FM3 family that features the industry's leading-edge ARM® Cortex®-M3TM CPU and integrates Cypress highly reliable and high-speed secure embedded flash technology. This MCU can operate at up to 80 MHz CPU frequency and work at a wide voltage range (2.7-5.5 V), which can be both compatible with 3.3 V and 5 V system.

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1 Introduction

1.1 About IEC60730

The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). International Standard IEC60730-1 has been prepared by IEC technical committee for automatic controls in household use. From 2007 onwards, home appliances will have to comply with Standard IEC60730 to make system more safety.

The Annex H of IEC60730 applies to electronic controls and embedded systems implemented by both hardware and software, therefore the system using a microcontroller is typically the case in modern appliances. Especially, Annex H of IEC60730 explains detailed test and diagnostic methods for microcontrollers.

In Annex H, the software-related Standard items are classified by Class A, B or C.

- Class A: control functions which are not intended to be relied upon for the safety of the equipment, such as humidity controls, lighting controls and timers.
- Class B: software that includes code intended to prevent hazards if a fault, other than a software fault, occurs in the appliance, such as thermal cut-outs and door locks for laundry equipment.
- Class C: software that includes code intended to prevent hazards without the use of other protective devices, such as thermal cut-outs for closed water heater systems.

1.2 About MB9B506 Series MCU

MB9B506 series MCU is 32-bit general purpose MCU of FM3 family that features the industry's leading-edge ARM Cortex-M3TM CPU and integrates Fujitsu's highly reliable and high-speed secure embedded flash technology. This MCU can operate at up to 80MHz CPU frequency and work at a wide voltage range (2.7-5.5 V), which can be both compatible with 3.3 V and 5 V system.

It includes a host of robust peripheral features, including motor control timers (MFT), base timer (can be configured to PWM, PPG, Reload, PWC timer), ADCs, on-chip memory (up to 512 K Flash, up to 64 K SRAM) and a wide range of communication interfaces (USB, I2C, SIO, LIN, CAN).

The size of on-chip memory can be configured according to different part number and the package is available in LQFP and BGA, shown in Table 1.

Table 1. FM3 Product List

Product	Flash	SRAM	Package
MB9BF500N/R	256kB	32kB	N: LQFP-100 R: LQFP-120
MB9BF504N/R	256kB	32kB	N: LQFP-100/BGA-112 R: LQFP-120
MB9BF505N/R	384kB	48kB	N: LQFP-100/BGA-112 R: LQFP-120
MB9BF506N/R	512kB	64kB	N: LQFP-100/BGA-112 R: LQFP-120

1.3 About FM3 IEC60730 STL Demo Project

This is a sample project to demonstrate how to use FM3 IEC60730 Self-Test Library. It is developed in IAR EWARM Workbench V6.21 and Keil µVision V4.21 IDE, and evaluated on IAR MB9BF506-SK EV-Board and Keil MCB9BF500 EV-Board (Vers.2) respectively.

Notes:

1. If the later version of IAR EWARM Workbench V6.21 and Keil µVision V4.21 are used to open this example project, MCU type information in project setting may lose, please check it.
2. If user select the “Use CMSIS” option (in Library Configuration table of General Options) with IAR EWARM Workbench V6.20 later, please erase the head files with prefix “core_” in common folder (path: ..\..\common).
3. If the former version of IAR EWARM Workbench V6.21 is used to open this example project, MCU type, pre-included files (in preprocess table of C/C++ compiler), icf file (in link table of debug option), flash loader file (down table of debugger option) may lose, please check these settings.
4. if the former version of Keil µVision V4.21 is used to open this example project, MCU type, pre-included files (in C/C++ table of project option), debug setting (in debug table of project setting) may lose, please check these information.
5. If user uses former version of IAR EWARM Workbench V6.20, it is a MUST to copy two files (core_cmFunc.h and core_cmInstr.h in cmsis_low_ver folder in current project directory) to common folder (path: ..\..\common).

1.4 About Document

This application notes describes how to use and implement the library functions provided. It will first show the requirement of IEC60730 Class B, and then explain how it can be implemented. At last an example is given to show to how to integrate test functions into a real system.

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2 IEC60730 Class B Requirement

The specification defined in IEC60730 requires controls with functions classified as software class B or C shall use measures to avoid and control software-related faults/errors in safety-related data and safety-related segments of the software. This means the software must use test method to detect faults internal and external of the microcontroller.

FM3 IEC60730 self test library (STL) focuses on software Class B requirement for MB9B506 series MCU, which covers most IEC60730 requirements listed in the standard. For Class B controllers, below table lists elements that must be tested, method to be adapted and definitions to be implemented as summary of Annex H table H.11.12.7.

Table 2. FM3 IEC60730 STL Test Items

Component	Fault/Error	Method used in STL	Definitions	In STL
1. CPU				
1.1 Register	Stuck at	static memory test	H. 2.19.6	YES
1.2 Program counter	Stuck at	logical monitoring of the program sequence	H.2.18.10.2	TES
2. Interrupt	No interrupt or too frequency interrupt	Time-slot monitoring	H.2.18.10.4	YES
3. Clock	Wrong frequency	Frequency monitor	H.2.18.10.1	YES
4. Memory				
4.1. Invariable memory	All single bit faults	Redundancy check	H.2.19.3.2	YES
	DC fault	static memory test	H.2.19.6	YES
4.2. Variable memory	Stuck at	Redundancy check	-	YES
4.3. Address[1]				
5. Internal data path[2]	Stuck at	-	-	NO
6.External communication				
6.1 Data[3]	Hamming distance 3	-	-	NO
6.3 Timing	Wrong point in time	-	-	NO
7. Input/output periphery				
7.1 Digital I/O	Function error	Output verification	H.2.18.12	YES
7.2 A/D	Function error	Input comparison	H.2.18.8	YES

Notes:

1. The address test can be partly covered by test method of invariable and variable memory test. E.g. the error that two cells are mapped to a same address can be identified when doing invariable memory test with CRC test.
2. Internal data path is only tested when using external memory.
3. The external communication test is not involved in this STL. But external communication data can be tested with similar method of invariable memory test.

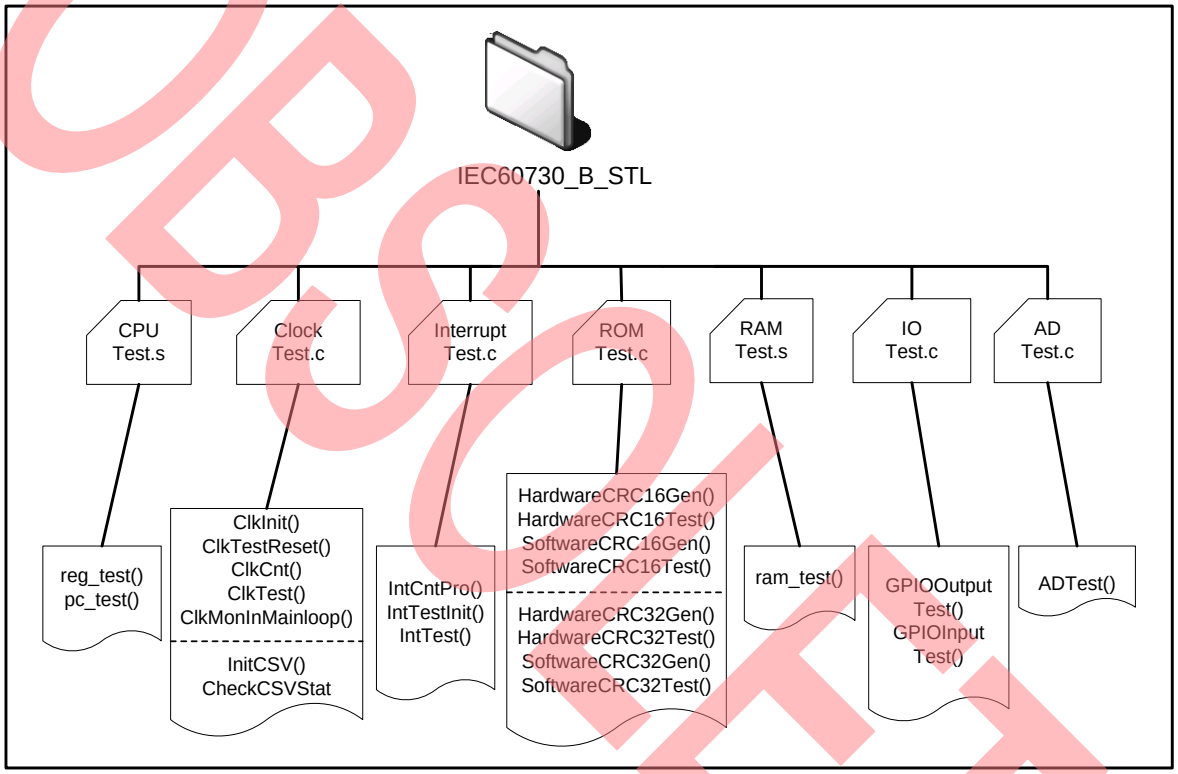
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3 IEC60730 Class B STL Overview

As shown in following figure, the STL block diagram includes CPU, Interrupt, Clock, Memory, and Input/output periphery module. It shows file structure and software APIs in the STL. The STL is coded by mixed C and assembly language.

FM3 IEC60730 STL should be compatible with ARM, IAR compiler. So STL supplies two kinds of CPU test.s and ram test.s files according to different compilers.

Figure 1. FM3 IEC60730 Class B STL Block Diagram



The STL consists of several independent function modules, which have to be executed once or cyclically as required by the application.

The test function implemented once is called Power-On Self-Test (POST), which should be implemented in system initialization, this test is always complete but destructive, which means it covers full test area but the data is not restored after executing test. PC, register, ROM/RAM, IO, AD test are all POST.

The test function implemented cyclically is called Build-In Self-Test (BIST), which should be implemented in main loop or timer interrupt service routine in a certain interval, this test will not change test data and act as a monitor when program is running. Interrupt and clock are BIST.

Notes:

1. The library should be used as explained, if any part is changed, a new validation is needed for these parts.
2. This library is usable, as-is, for all Fujitsu Cotex-M3 MCU, including those not especially mentioned in this application notes.
3. The prefix of file and function name is omitted for easy description.
4. The STL provides two types of assembly files for CPU and RAM test for IAR and Keil IDE.
5. User has alternative test method in clock and Flash test.

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4 IEC60730 Class B STL API

4.1 CPU Register Test

ARM Cotex-M3 has 19 core registers, which can be read and written. These registers need to be tested.

Table 3. Cotex-M3 Register List

Register Name	Bits tested
R0-R12	[31:0]
R13 (SP_main, SP_process)[1]	[31:4]
R14 (LR)	[31:0]
APSR[2]	[31:27]
PRIMASK[3]	0
FAULTMASK[4]	0
BASEPRI[5]	[7:4]

Notes:

1. ARM Cotex-M3 kernel has two stack pointers: main stack pointer (MSP) and process stack pointer (PSP). Handler mode uses MSP and process mode uses MSP or PSP. R13 indicates current SP.
2. Only high 5 bits of APSR is valid.
3. Only bit 0 of PRIMASK is valid.
4. Only bit 0 of FAULTMASK is valid.
5. 16 interrupt priority levels can be configured by bit [7:4] of Interrupt Priority Registers in FM3 MCU, so only bit [7:4] of BASEPRI can be used to mask user interrupt.

4.1.1 Test Description

As shown at table H.11.12.7, registers must be checked for “stuck-at error”, a simple checkerboard method is used to implement register test, which is an effective method to detect stuck-at error.

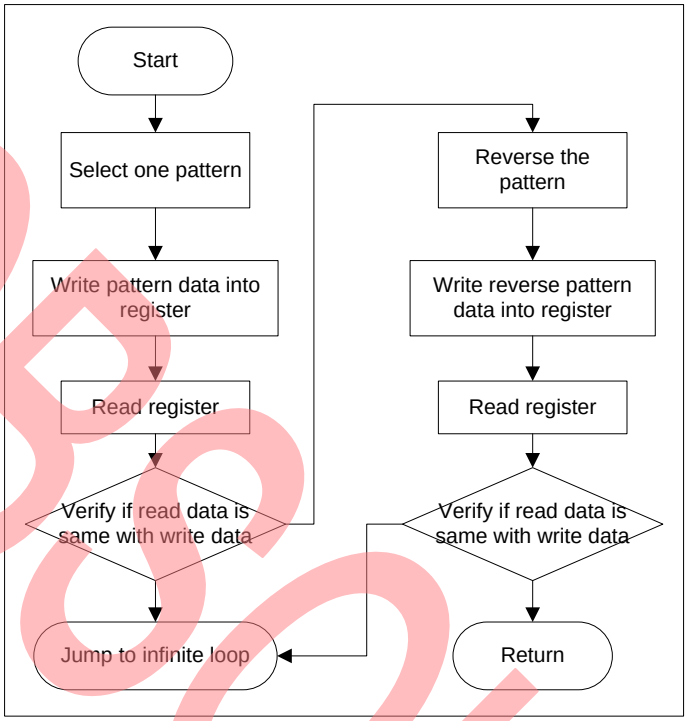
This test should be called at startup file when system resets in Privileged mode, as kernel registers needs to be accessed. This test does not disable interrupts during the register test. It is the responsibility of the application to disable interrupts when this function is called to ensure that the register test is not interrupted.

Assembly is used to implement register test due to access to registers directly. And as it is highly critical, it is designed that once register test error is detected, program will run into an infinite loop.

The flow chart to test 1 register is shown as following figure.

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Figure 2. Test 1 Register



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4.1.2 API Definition

Name	iec60730_reg_test
Parameter	None
Return	None

Description:

This function tests all registers including R0-R12 (low:R0-R7,high:R8-R12) special registers (SP, LR, APSR, PRIMASK, FAULTMASK, BASEPRI) with checkerboard method. This function should be called at reset handler.

4.2 CPU PC Test

4.2.1 Test Description

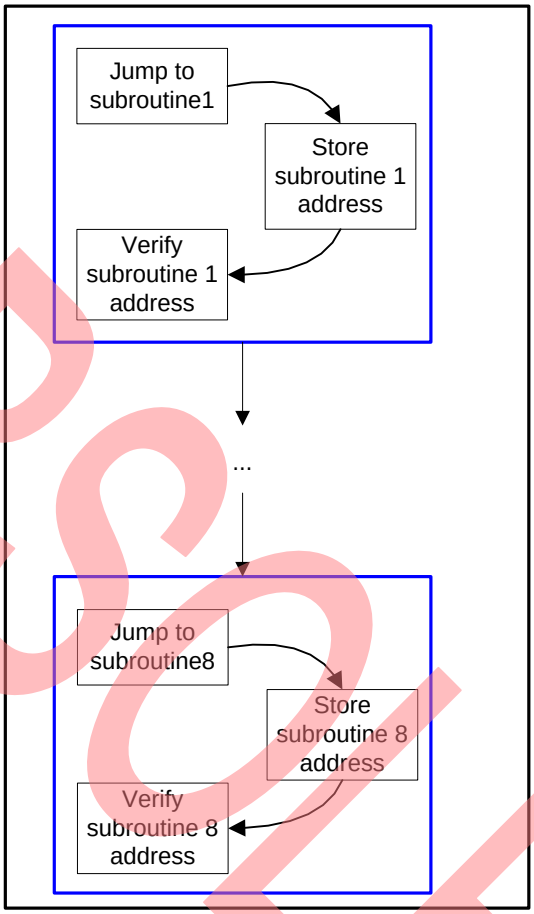
As shown at table H.11.12.7, PC must be checked for “stuck-at error”. PC test makes use of 8 subroutines and validates if PC value gotten from each subroutines is same with pre-define value.

This test should be called at startup file when system resets in Privileged mode. This test does not disable interrupts during the register test. It is the responsibility of the application to disable interrupts when this function is called to ensure that the register test is not interrupted.

Assembly is used to implement PC test due to access to PC register directly. As it is highly critical, it is designed that once PC test error is detected, program will run into an infinite loop.

The PC test flow is shown as following figure.

Figure 3. PC Test Flow Chart



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4.2.2 API Definition

Name	iec60730_pc_test
Parameter	None
Return	None

Description:

This function jumps to subroutines at different areas and gets the subroutine address, then verifies if address gotten is correct. It should be called at reset handler.

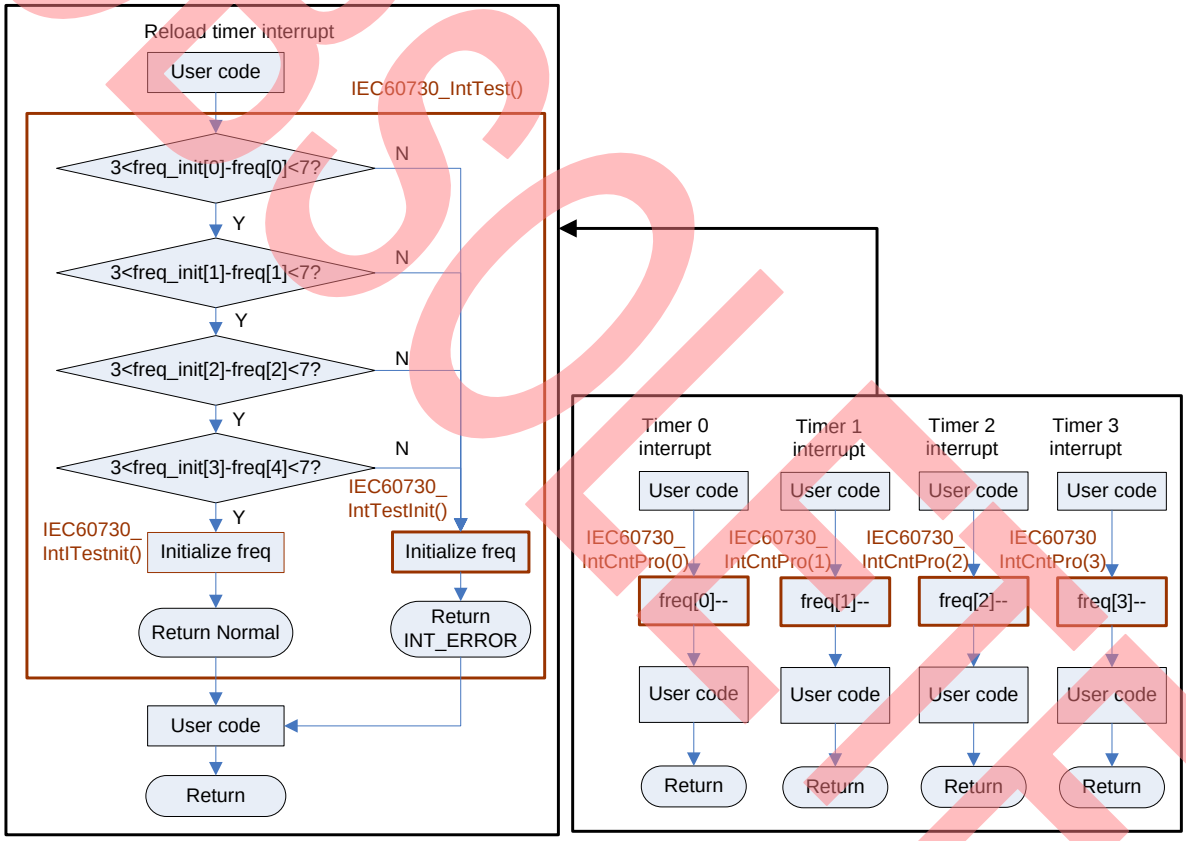
4.3 Interrupt Test

4.3.1 Test Description

To meet Class B requirement, interrupt must be checked for “incorrect frequency”. This test is a task which is highly system dependent and therefore the STL can only contribute the wrap up handle, which checks that a number of specific interrupts occurred at least and at most a predefined number of times. It is assumed that **IEC60730_IntTest** (interrupt test function) is called in specified intervals, e.g. triggered by a timer or line frequency interrupt. Each specific interrupt handler which is to be supervised, must decrement a dedicated global variable (**Freq**) by calling **IEC60730_IntCnt**, **IEC60730_IntTest** compares that variable to predefined upper and lower bounds, sets it to its preset value and returns an error, if the limits are exceeded.

For example, measure if timer0-3 interrupts happen 5 times in 10 second, assume 10 second timing can be gotten by a reload timer and set the range of interrupt frequency of timer 0-3 at [3, 7].

Figure 4. Interrupt Test Block Diagram



The interrupt test is independent from user application. User just need to add the interrupt test API into his interrupt which he wants to test.

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4.3.2 API Definition

Name	IEC60730_IntTestInit
Parameter	pFreq: pointer to frequency counters pFreqLower: pointer to lower frequencies pFreqUpper: pointer to upper frequencies pFreqInitial: pointer to frequency initial value ArraySize: pointer to interrupt num
Return	None

Description:

This function Initializes str_int_test_par_t structure for interrupt test, which includes pre-defined frequency ranges and frequency initial values. It should be called at system initialization, before interrupt test starts.

Name	IEC60730_IntCntPro
Parameter	IntNum: interrupt number
Return	None

Description:

This function decreases frequency counter of the interrupt specified by the interrupt number, and should be called in the interrupt which to be supervised.

Name	**IEC60730_IntTest**
Parameter	None
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This is interrupt test main function, which verifies if interrupts are handled in time. It should be called at a timer interrupt or main loop in a certain interval.

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4.4 Clock Test

4.4.1 Test Description

To meet Class B requirement, CPU clock must be checked for “wrong frequency”. This requires a second independent clock as a standard clock for clock test. This library provides two ways to implement clock test. First, FM3 MCU has integrated a watch counter which can be sourced by an external sub clock (32.768 kHz oscillator). The sub clock can be treated as the standard clock. For the second, FM3 MCU has integrated a **Clock Supervisor** (in following called **CSV**), which includes the functions: Clock failure detection and Anomalous frequency detection. The CSV can also be used for clock test.

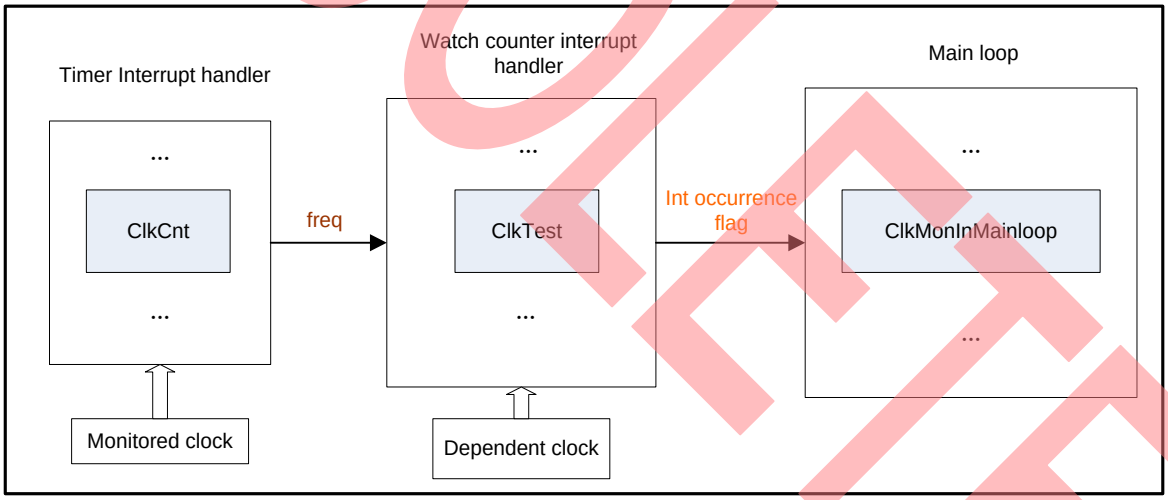
User should enable the definition “IEC60730_CLKTEST_USE_CSV” in IEC60730_user.h file if he wants to use CSV to perform clock test.

- **Use watch counter to do clock test**

This test takes watch counter as standard clock, and tests if the frequency of CPU clock is within acceptable bound by verifying a time tick which is counted in a timer interrupt. The source clock of timer interrupt should be same with CPU clock. The case that CPU clock is sourced by sub clock cannot be tested, as 32.768 kHz oscillator is assumed accurate.

These test functions are implemented: **IEC60730_ClkCnt**, **IEC60730_ClkTest**, and **IEC60730_ClkMonMainloop**, shown as following figure. The timer interrupt occurrence frequency is monitored by watch counter and the watch counter interrupt occurrence is checked in main loop.

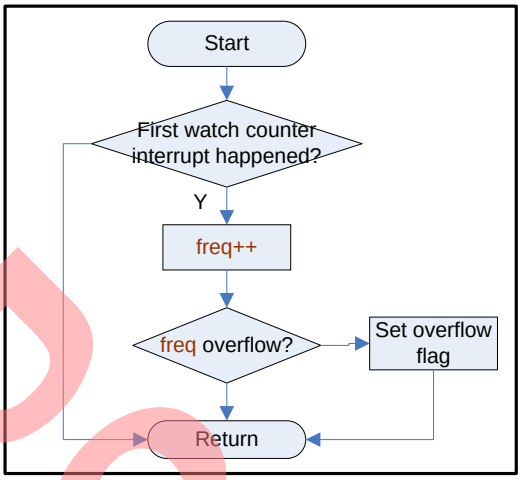
Figure 5. Clock Test Block Diagram



The API **IEC60730_ClkCnt** is used to count a global variable “freq”, which is called in a timer interrupt handler, the source clock of timer should be same with CPU clock. The flowchart of **IEC60730_ClkCnt** is shown as following figure.

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Figure 6. Clock Counter Flowchart

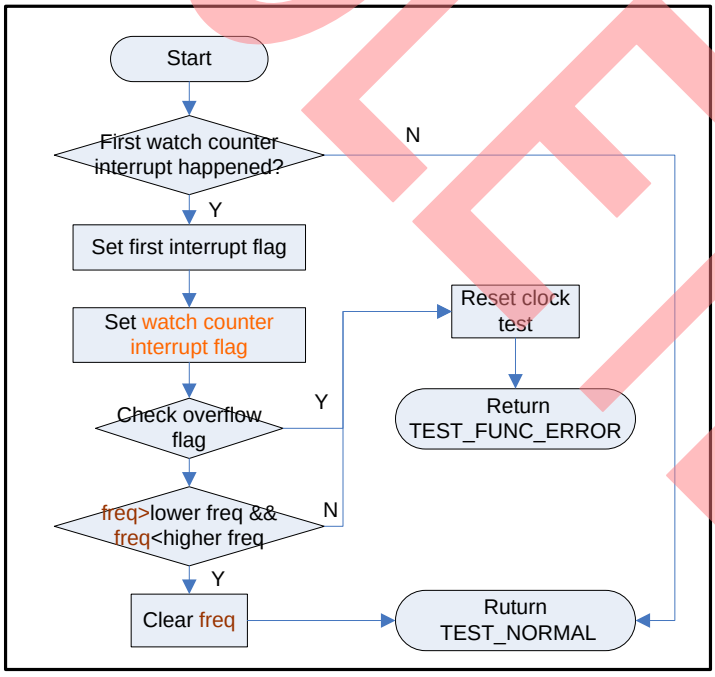


Notes:

1. The global variable “freq” starts to count until first watch counter interrupt occurred, because it is a limitation of watch counter in FM3 MCU that the first count cycle is 2 times of normal cycle. So the first watch counter interrupt should be ignored.

API **IEC60730_ClkTest** is to check if “freq” is in pre-defined range, which is called in watch counter interrupt handler.

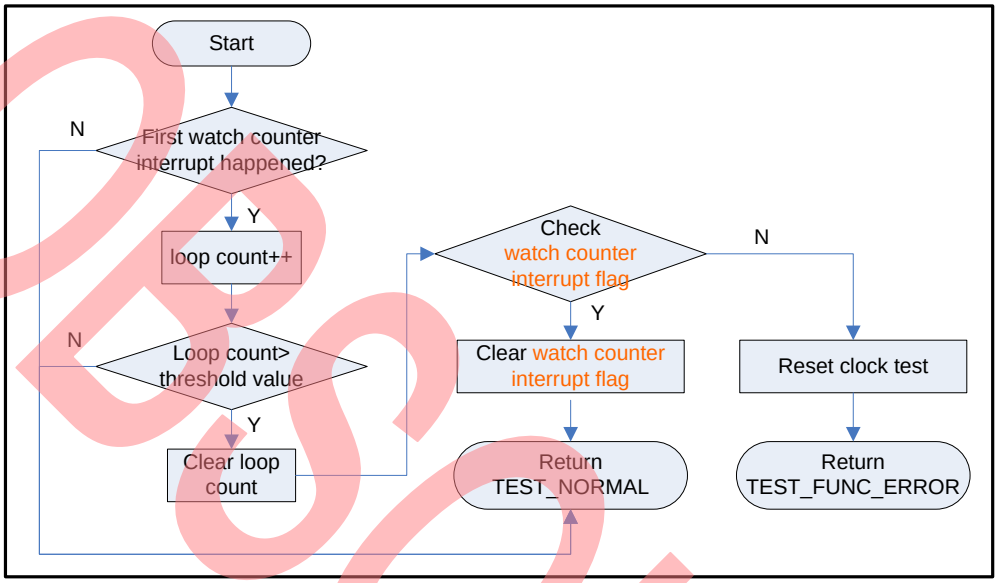
Figure 7. Clock Test Flowchart



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API **IEC60730_ClkMonInMainloop** guarantees the occurrence of watch counter interrupt in a certain period, this period depends on the threshold value set by user according to a real application. The flowchart of **IEC60730_ClkMonMainInloop** is shown as following figure.

Figure 8. Clock Main Loop Monitor Flowchart



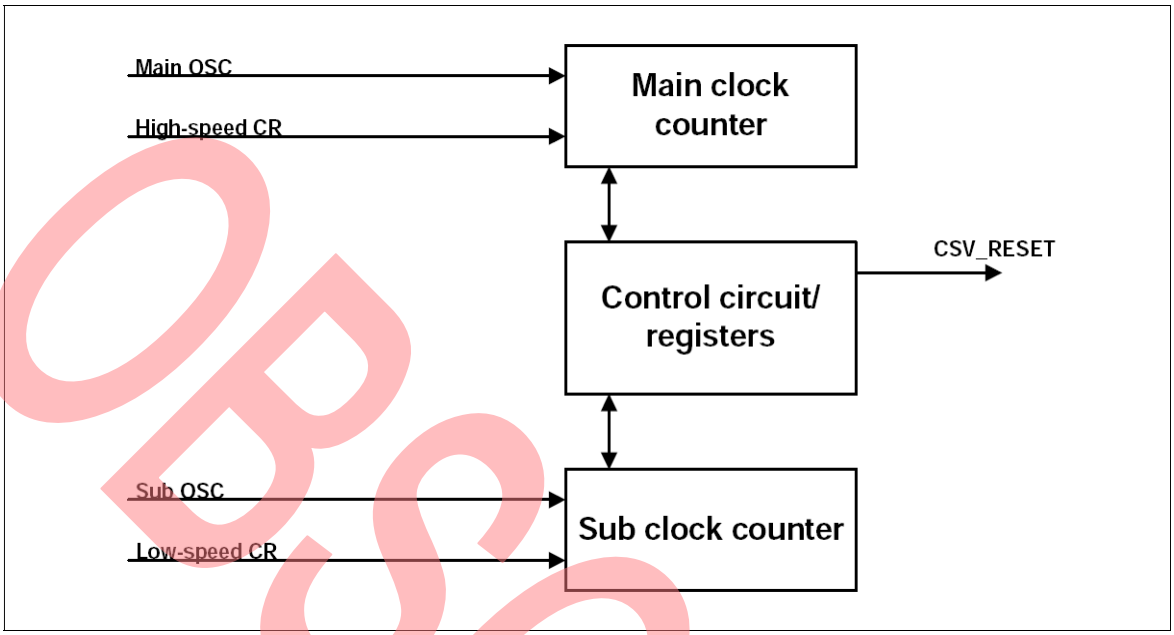
■ **Use CSV to do clock test**

The CSV has two types of functions: **Clock failure detection** (**CSV**: Clock failure detection by clock Super Visor) and **Anomalous frequency detection** (**FCS**: anomalous Frequency detection by Clock Super visor).

The clock failure detection monitors the main and sub clocks. If a rising edge of the monitored clock is not detected within the specified period, this function determines that the oscillator has failed, and outputs a system reset request. The main clock is monitored with the high-speed CR clock, and the sub clock is monitored with the low-speed CR clock. When a rising edge is not detected within 32 clocks of high-speed CR for the main clock, or within 32 clocks of low-speed CR for the sub clock, this function determines that the oscillator has failed. Figure 9. Clock Failure Detection Block Diagram shows the block diagram of the clock failure detection.

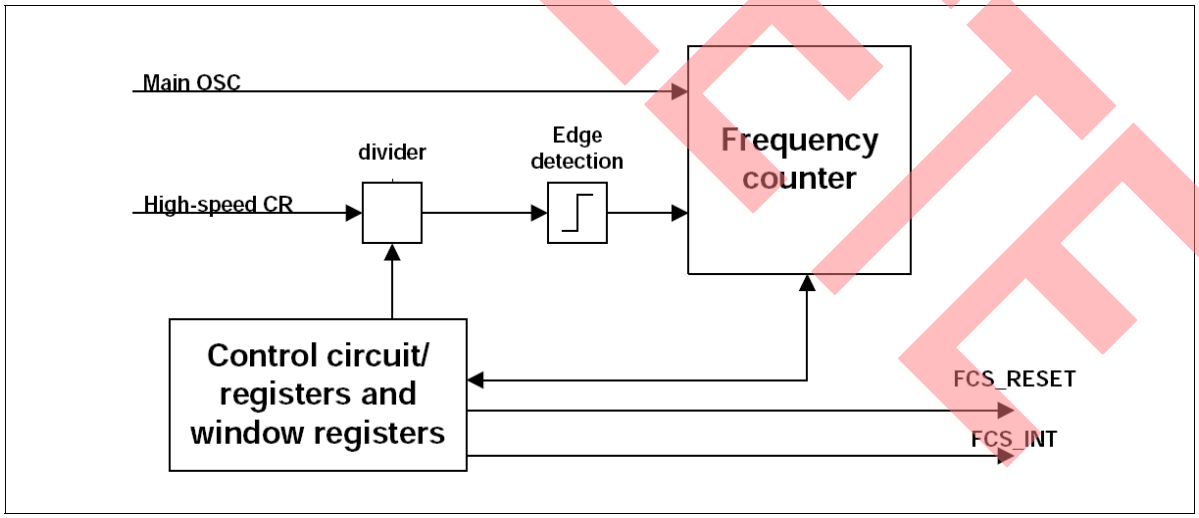
OBSOLETE

Figure 9. Clock Failure Detection Block Diagram



The Anomalous frequency detection monitors the main clock. Within the specified period between an edge and the next edge of the divided clock of high-speed CR, this function counts up the internal counter using the main clock. If the count value reaches out of the set window range, the function determines that the main clock frequency is anomalous, and outputs an interrupt request or a system reset request to the CPU. Figure 10. Anomalous Frequency Detection Block Diagram shows the block diagram of the anomalous frequency detection.

Figure 10. Anomalous Frequency Detection Block Diagram

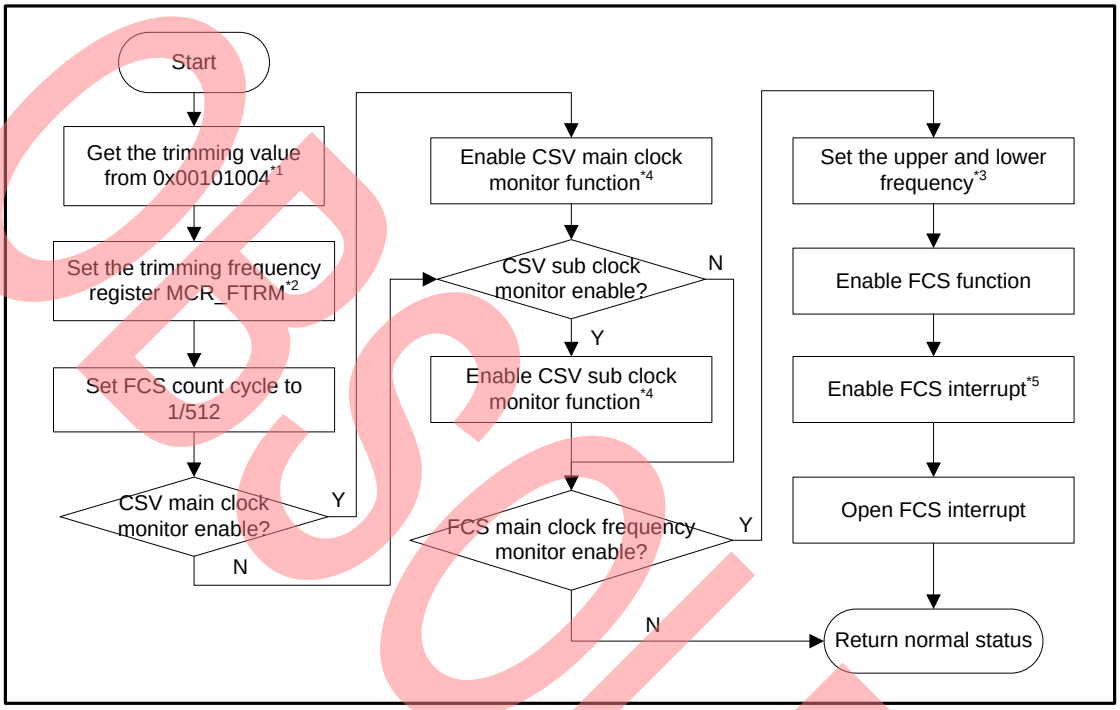


Two test functions are implemented: **IEC60730_InitCSV** and **IEC60730_CheckCSVStat.**

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The API **IEC60730_InitCSV** provides a selection for user to disable/enable Clock failure detection and Anomalous frequency detection functions. It should be called before system clock initialization. Figure 11. IEC60730_InitCSV Flow Chart shows the flow chart of it.

Figure 11. IEC60730_InitCSV Flow Chart



Notes:

1. The default high-speed CR trimming value is stored in the address 0x00101004 when leaving factory.
2. If the CR trimming value in the address 0x00101004 is destroyed, a typical value will be written into the trimming register MCR_FTRM. (For MB9BF500 this value is 0x67, and for other MCU this value is 0x016B).
3. When setting the expected accuracy of main clock, high-speed CR frequency should also be considered. Consider the high-speed CR oscillator precision is 4M±3% (As found in data sheet, for MB9BF500, the high-speed CR oscillator precision is 4M±3%, and for the other MCU, it is 4M±2% in 25°C, so 4M±3% is used for a little margin). The base upper and lower count can be calculated by following formula.

   base lower count (operating in +3.0%) = 1/[(freq/512*) × (1 + 0.03)] × freq = 512/1.03 = 497

   base upper count (operating in -3.0%) = 1/[(freq/512*) × (1 - 0.03)] × freq = 512/0.97 = 528

   If 5% accuracy is set,

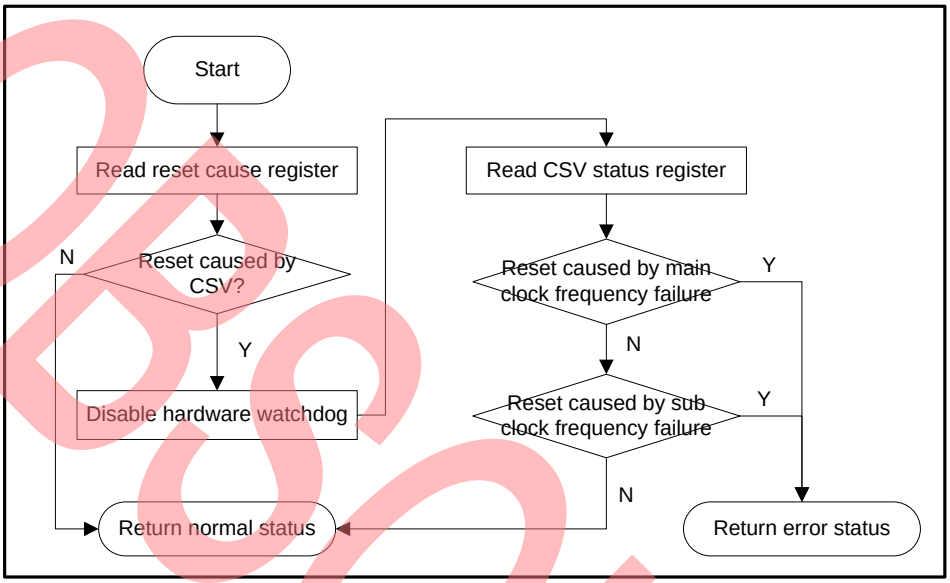
   lower count = 497 × 0.95 = 472

   upper count = 528 × 1.05 = 554
4. After enable CSV function, a reset will occurred when a rising edge is not detected within 32 clocks of high-speed CR for the main clock, or within 32 clocks of low-speed CR for the sub clock.
5. After enable FCS function and FCS interrupt, a FCS interrupt will occur if main clock frequency is detected not in the setting range, but FCS reset is set not to output.

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The API **IEC60730_CheckCSVStat** is used to check if Clock failure detection or Anomalous frequency detection happens. This API should be called before **IEC60730_InitCSV.** Figure 12. IEC60730_CheckCSVStat Flow Chart shows the flow chart of it.

Figure 12. IEC60730_CheckCSVStat Flow Chart



OBSOLETE

4.4.2 API Definition

- **Use watch counter to do clock test**

Name	IEC60730_ClkCnt
Parameter	None
Return	None

Description:

This API is used to count clock frequency, which should be called in the timer interrupt.

Name	IEC60730_ClkTest
Parameter	None
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API tests if the frequency of CPU clock is within acceptable bound by verifying a time tick which is counted in a timer interrupt. It should be called in the watch counter interrupt, which is sourced by an independent 32.768 kHz clock (sub-clock of FM3 MCU).

Name	IEC60730_ClkMonInMainloop
Parameter	None
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API is used to monitor watch counter interrupt occurrence, it should be called in main loop.

Name	IEC60730_ClkTestReset
Parameter	None
Return	None

Description:

This API resets interrupt test variables.

Name	IEC60730_ClkInit
Parameter	FreqLower: indicate timer interrupt minimum occur frequency FreqUpper: indicate timer interrupt maximum occur frequency ClkTestThreshold: indicate threshold value
Return	None

Description:

This API should be called at system initialization before clock test starts.

The parameter FreqLower and FreqUpper should be set according to actual example. For example, if user uses 1s interval for watch counter to monitor a 50 ms timer interrupt. The value FreqLower =18, FreqUpper =22 can be set as bound of timer clock frequency, the standard of which is 20.

It is important to estimate threshold value, which should be at least 1s/mainloop execution time.

- **Use CSV to do clock test**

Name	IEC60730_CheckCSVStat
Parameter	pRegRSTStat: get the data from reset cause register
Return	None

Description:

This API is used to check if Clock failure detection or anomalous frequency detection happens. The parameter “pRegRSTStat” store the address of data read from reset cause register. This API only handles the reset caused by CSV, otherwise it will return normal status. It should be called before IEC60730_InitCSV.

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Name	IEC60730_InitCSV
Parameter	CSV_MCLKMonEn: 0: disable CSV main clock monitor 1:enable CSV main clock monitor CSV_SCLKMonEn: 0: disable CSV sub clock monitor 1:enable CSV sub clock monitor FCS_MONInfo: a fcs_mon_info_t structure typedef struct fcs_mon_info { stl_uint8_t FCSMonEn; /* 0: disable FCS function, 1: enable FCS function */ stl_uint8_t MCLKFreqAccuracy; /* input the excepted accuracy of main clock, 5->5%*/ } fcs_mon_info_t;
Return	0: IEC60730_TEST_NORMAL 2: IEC60730_TEST_PARA_ERROR

Description:

This API can enable/disable CSV main/sub clock function, and input the expected accuracy of main clock frequency. It should be called before system clock initialization.

4.5 Invariable Memory Test

Invariable memory in FM3 MCU means On-Chip Flash. The Flash size can be configured according to different product shown as Table 1.

FM3 MCU integrates an On-Chip CRC module. The CRC (Cyclic Redundancy Check) module is an error detection system. The CRC code is a remainder after an input data string is divided by the pre-defined generator polynomial, assuming the input data string is a high order polynomial. Ordinarily, a data string is suffixed by a CRC code when being sent, and the received data is divided by a generator polynomial as described above. If the received data is dividable, it is judged to be correct.

This module can either use CCITT CRC16 or IEEE-802.3 CRC32, which can be configured by CRCCR: CRC32 bit. In this module, the generator polynomials is fixed to the numeric values for those two modes.

- CCITT CRC16 generator polynomial: 0x1021
- IEEE-802.3 CRC32 generator polynomial: 0x04C11DB7

4.5.1 Test Description

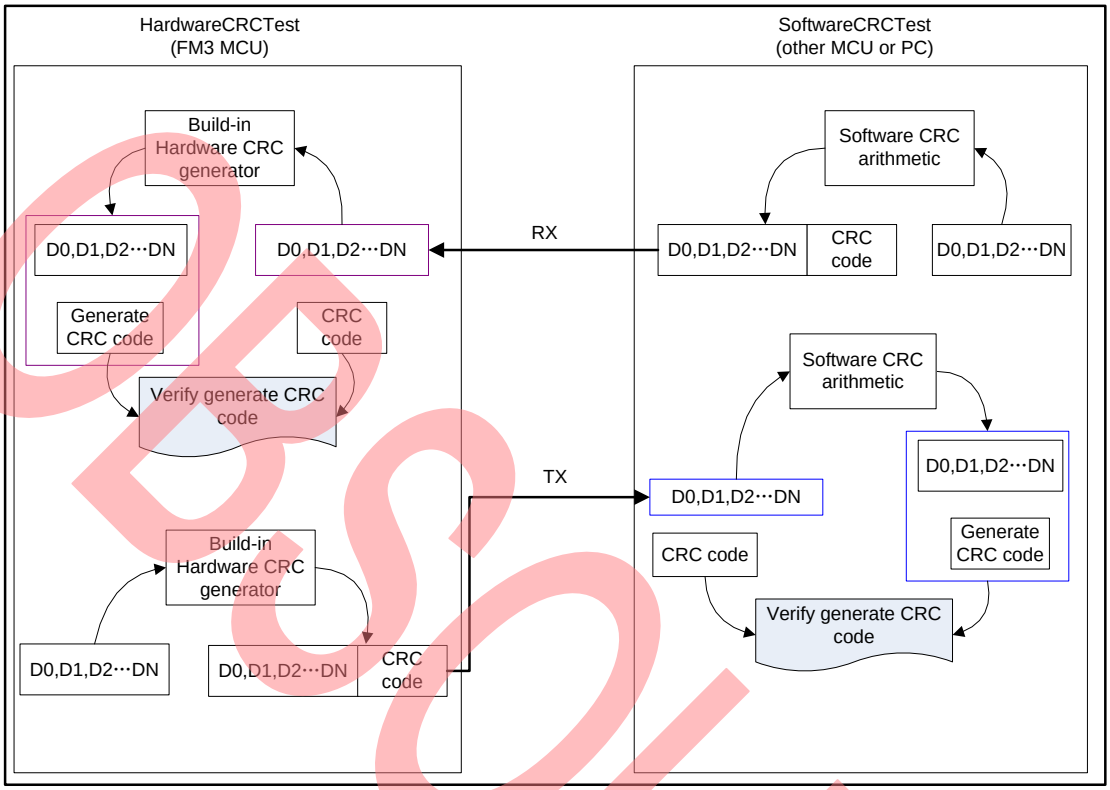
To meet Class B requirement, Flash test must be checked for “single bit fault”. This test can be implemented as CRC16/32 test. On-Chip CRC module is used to implement hardware CRC16/32 test, and software CRC16/32 are also provided with same implementation arithmetic as hardware CRC.

Enable the definition “FLASH_TEST_USE_CRC16” in IEC60730_user.h file if user wants to use CRC16 arithmetic for Flash test, otherwise CRC32 arithmetic will be implemented.

This test can be implemented at startup procedure to test whole code area, or it can also be called periodically to test sub blocks. Following shows an application of CRC test when FM3 MCU communicates with other devices.

OBSOLETE

Figure 13. Clock Main Loop Monitor Flowchart



Notes:

The CRC can also be used to test external communication data, which fulfills H.2.19.4.1 to detect hamming distance 3 error.

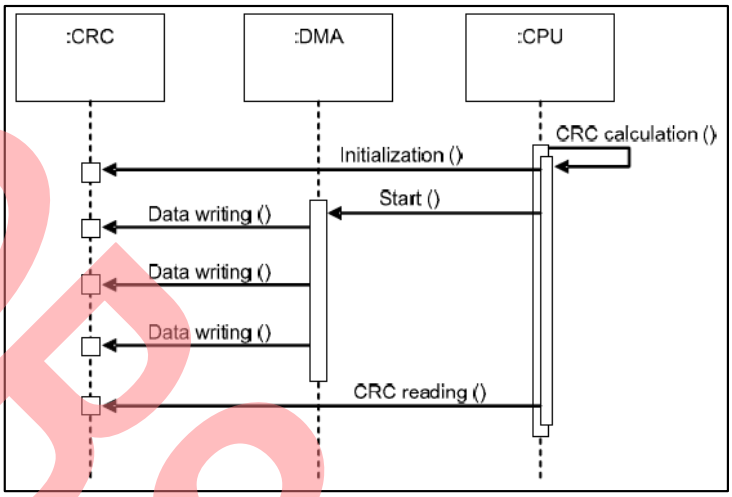
■ Hardware CRC

The procedure to generator CRC code with hardware CRC module can be described as following steps.

1. Initial CRC control register CRCCR and initial value register CRCINIT
2. Write “1” to the initial value bit (CRCCR:INIT). The value of CRCINIT is loaded into CRC register CRCR.
3. Write data into input data register CRCIN continuously. Then CRC calculation starts. To obtain a CRC code, read the CRC register (CRCR).

OBSOLETE

Figure 14. Clock Main Loop Monitor Flowchart



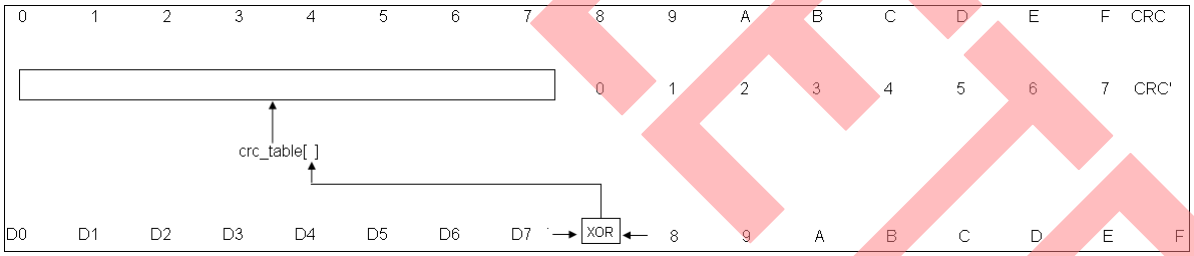
- **Software CRC**

  - **Software CRC16 Arithmetic**

The CRC table enquiry method is used. The software CRC16 arithmetic should implement 3 steps to generate a new CRC code with 1 byte data.

1. Right shift 8 bits of the original CRC code, and save it as “temp”
2. Get table index by XOR the high byte with test data
3. Generate new CRC code by OR “temp” with the data gotten from CRC table.

Figure 15. Generate New CRC16 Code



The software CRC16 generation code and CRC16 table is shown as following figure.

OBSOLETE

Figure 16. Software CRC16 Generation Source Code

```
stl_uint16_t IEC60730_SoftwareCRC16Gen(stl_uint8_t *pData, stl_uint32_t Size)
{
    stl uint8 t temp;
    stl uint8 t *p temp data = pData;
    stl uint16 t crc = 0xFFFF;
    while(Size-- != 0)
    {
        temp = crc/256;
        crc <<=8;
        crc ^= CRCTable[temp^*p temp data];
        p temp data++;
    }
    return crc;
}
```

Figure 17. CRC16 table

```
const stl_uint16_t crc_table[256]={
    0x0000, 0x1021, 0x2042, 0x3063, 0x4084, 0x50A5, 0x60C6, 0x70E7,
    0x8108, 0x9129, 0xA14A, 0xB16B, 0xC18C, 0xD1AD, 0xE1CE, 0xF1EF,
    0x1231, 0x0210, 0x3273, 0x2252, 0x52B5, 0x4294, 0x72F7, 0x62D6,
    0x9339, 0x8318, 0xB37B, 0xA35A, 0xD3BD, 0xC39C, 0xF3FF, 0xE3DE,
    0x2462, 0x3443, 0x0420, 0x1401, 0x64E6, 0x74C7, 0x44A4, 0x5485,
    0xA56A, 0xB54B, 0x8528, 0x9509, 0xE5EE, 0xF5CF, 0xC5AC, 0xD58D,
    0x3653, 0x2672, 0x1611, 0x0630, 0x76D7, 0x66F6, 0x5695, 0x46B4,
    0xB75B, 0xA77A, 0x9719, 0x8738, 0xF7DF, 0xE7FE, 0xD79D, 0xC7BC,
    0x48C4, 0x58E5, 0x6886, 0x78A7, 0x0840, 0x1861, 0x2802, 0x3823,
    0xC9CC, 0xD9ED, 0xE98E, 0xF9AF, 0x8948, 0x9969, 0xA90A, 0xB92B,
    0x5AF5, 0x4AD4, 0x7AB7, 0x6A96, 0x1A71, 0x0A50, 0x3A33, 0x2A12,
    0xDBFD, 0xCBDC, 0xFBBF, 0xEB9E, 0x9B79, 0x8B58, 0xBB3B, 0xAB1A,
    0x6CA6, 0x7C87, 0x4CE4, 0x5CC5, 0x2C22, 0x3C03, 0x0C60, 0x1C41,
    0xEDAE, 0xFD8F, 0xCDEC, 0xDDCD, 0xAD2A, 0xBD0B, 0x8D68, 0x9D49,
    0x7E97, 0x6EB6, 0x5ED5, 0x4EF4, 0x3E13, 0x2E32, 0x1E51, 0x0E70,
    0xFF9F, 0xEFBE, 0xDFDD, 0xCFFC, 0xBF1B, 0xAF3A, 0x9F59, 0x8F78,
    0x9188, 0x81A9, 0xB1CA, 0xA1EB, 0xD10C, 0xC12D, 0xF14E, 0xE16F,
    0x1080, 0x00A1, 0x30C2, 0x20E3, 0x5004, 0x4025, 0x7046, 0x6067,
    0x83B9, 0x9398, 0xA3FB, 0xB3DA, 0xC33D, 0xD31C, 0xE37F, 0xF35E,
    0x02B1, 0x1290, 0x22F3, 0x32D2, 0x4235, 0x5214, 0x6277, 0x7256,
    0xB5EA, 0xA5CB, 0x95A8, 0x8589, 0xF56E, 0xE54F, 0xD52C, 0xC50D,
    0x34E2, 0x24C3, 0x14A0, 0x0481, 0x7466, 0x6447, 0x5424, 0x4405,
    0xA7DB, 0xB7FA, 0x8799, 0x97B8, 0xE75F, 0xF77E, 0xC71D, 0xD73C,
    0x26D3, 0x36F2, 0x0691, 0x16B0, 0x6657, 0x7676, 0x4615, 0x5634,
    0xD94C, 0xC96D, 0xF90E, 0xE92F, 0x99C8, 0x89E9, 0xB98A, 0xA9AB,
    0x5844, 0x4865, 0x7806, 0x6827, 0x18C0, 0x08E1, 0x3882, 0x28A3,
    0xCB7D, 0xDB5C, 0xEB3F, 0xFB1E, 0x8BF9, 0x9BD8, 0xABBB, 0xBB9A,
    0x4A75, 0x5A54, 0x6A37, 0x7A16, 0x0AF1, 0x1AD0, 0x2AB3, 0x3A92,
    0xFD2E, 0xED0F, 0xDD6C, 0xCD4D, 0xBDAA, 0xAD8B, 0x9DE8, 0x8DC9,
    0x7C26, 0x6C07, 0x5C64, 0x4C45, 0x3CA2, 0x2C83, 0x1CE0, 0x0CC1,
    0xEF1F, 0xFF3E, 0xCF5D, 0xDF7C, 0xAF9B, 0xBFBA, 0x8FD9, 0x9FF8,
    0x6E17, 0x7E36, 0x4E55, 0x5E74, 0x2E93, 0x3EB2, 0x0ED1, 0x1EF0
};
```

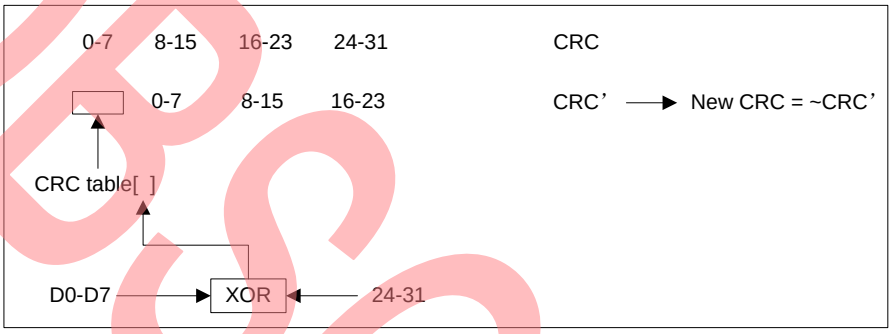
OBSOLETE

- **Software CRC32 Arithmetic**

The CRC table enquiry method is used. The software CRC32 arithmetic should implement 4 steps to generate a new CRC code with 1 byte data.

1. Right shift 8 bits of the original CRC code, and save it as “temp”
2. Get table index by XOR the high 8 bits with test data
3. Generate temp CRC code by OR “temp” with the data gotten from CRC table.
4. Get new CRC code by reverse temp CRC code.

Figure 18. Generate New CRC32 Code



The software CRC32 generation code and CRC32 table is shown as following figure.

Figure 19. Software CRC32 Generation Source Code

```
stl uint32 t IEC60730 SoftwareCRC32Gen(stl uint8 t *pData, stl uint32 t Size)
{
    stl uint8 t temp;
    stl uint8 t *p temp data = pData;
    stl uint32 t crc = 0xFFFFFFFF;
    while(Size--)
    {
        temp=( crc >> 24 );
        crc = ( crc << 8 ) ^ CRCTable[temp^*p temp data];
        p temp data++;
    }
    return ~crc;
}
```

OBSOLETE

Figure 20. CRC32 table

```
const stl uint32 t CRCTable[256]={
    0x00000000L,  0x04c11db7L,  0x09823b6eL,  0x0d4326d9L,
    0x130476dcL,  0x17c56b6bL,  0x1a864db2L,  0x1e475005L,
    0x2608edb8L,  0x22c9f00fL,  0x2f8ad6d6L,  0x2b4bcb61L,
    0x350c9b64L,  0x31cd86d3L,  0x3c8ea00aL,  0x384fbdbdL,
    0x4c11db70L,  0x48d0c6c7L,  0x4593e01eL,  0x4152fda9L,
    0x5f15adacL,  0x5bd4b01bL,  0x569796c2L,  0x52568b75L,
    0x6a1936c8L,  0x6ed82b7fL,  0x639b0da6L,  0x675a1011L,
    0x791d4014L,  0x7ddc5da3L,  0x709f7b7aL,  0x745e66cdL,
    0x9823b6e0L,  0x9ce2ab57L,  0x91a18d8eL,  0x95609039L,
    0x8b27c03cL,  0x8fe6dd8bL,  0x82a5fb52L,  0x8664e6e5L,
    0xbe2b5b58L,  0xbaea46efL,  0xb7a96036L,  0xb3687d81L,
    0xad2f2d84L,  0xa9ee3033L,  0xa4ad16eaL,  0xa06c0b5dL,
    0xd4326d90L,  0xd0f37027L,  0xddb056feL,  0xd9714b49L,
    0xc7361b4cL,  0xc3f706fbL,  0xceb42022L,  0xca753d95L,
    0xf23a8028L,  0xf6fb9d9fL,  0xfbb8bb46L,  0xff79a6f1L,
    0xe13ef6f4L,  0xe5ffeb43L,  0xe8bccd9aL,  0xec7dd02dL,
    0x34867077L,  0x30476dc0L,  0x3d044b19L,  0x39c556aeL,
    0x278206abL,  0x23431b1cL,  0x2e003dc5L,  0x2ac12072L,
    0x128e9dcfL,  0x164f8078L,  0x1b0ca6a1L,  0x1fcdbb16L,
    0x018aeb13L,  0x054bf6a4L,  0x0808d07dL,  0x0cc9cdcaL,
    0x7897ab07L,  0x7c56b6b0L,  0x71159069L,  0x75d48ddeL,
    0x6b93dddbL,  0x6f52c06cL,  0x6211e6b5L,  0x66d0fb02L,
    0x5e9f46bfL,  0x5a5e5b08L,  0x571d7dd1L,  0x53dc6066L,
    0x4d9b3063L,  0x495a2dd4L,  0x44190b0dL,  0x40d816baL,
    0xaca5c697L,  0xa864db20L,  0xa527fdf9L,  0xa1e6e04eL,
    0xbfa1b04bL,  0xbb60adfcL,  0xb6238b25L,  0xb2e29692L,
    0x8aad2b2fL,  0x8e6c3698L,  0x832f1041L,  0x87ee0df6L,
    0x99a95df3L,  0x9d684044L,  0x902b669dL,  0x94ea7b2aL,
    0xe0b41de7L,  0xe4750050L,  0xe9362689L,  0xedf73b3eL,
    0xf3b06b3bL,  0xf771768cL,  0xfa325055L,  0xfef34de2L,
    0xc6bcf05fL,  0xc27dede8L,  0xcf3ecb31L,  0xcbffd686L,
    0xd5b88683L,  0xd1799b34L,  0xdc3abdedL,  0xd8fba05aL,
    0x690ce0eeL,  0x6dcdfd59L,  0x608edb80L,  0x644fc637L,
    0x7a089632L,  0x7ec98b85L,  0x738aad5cL,  0x774bb0ebL,
    0x4f040d56L,  0x4bc510e1L,  0x46863638L,  0x42472b8fL,
    0x5c007b8aL,  0x58c1663dL,  0x558240e4L,  0x51435d53L,
    0x251d3b9eL,  0x21dc2629L,  0x2c9f00f0L,  0x285e1d47L,
    0x36194d42L,  0x32d850f5L,  0x3f9b762cL,  0x3b5a6b9bL,
    0x0315d626L,  0x07d4cb91L,  0x0a97ed48L,  0x0e56f0ffL,
    0x1011a0faL,  0x14d0bd4dL,  0x19939b94L,  0x1d528623L,
    0xf12f560eL,  0xf5ee4bb9L,  0xf8ad6d60L,  0xfc6c70d7L,
    0xe22b20d2L,  0xe6ea3d65L,  0xeba91bbcL,  0xef68060bL,
    0xd727bbb6L,  0xd3e6a601L,  0xdea580d8L,  0xda649d6fL,
    0xc423cd6aL,  0xc0e2d0ddL,  0xcda1f604L,  0xc960ebb3L,
    0xbd3e8d7eL,  0xb9ff90c9L,  0xb4bcb610L,  0xb07daba7L,
    0xae3afba2L,  0xaafbe615L,  0xa7b8c0ccL,  0xa379dd7bL,
    0x9b3660c6L,  0x9ff77d71L,  0x92b45ba8L,  0x9675461fL,
    0x8832161aL,  0x8cf30badL,  0x81b02d74L,  0x857130c3L,
    0x5d8a9099L,  0x594b8d2eL,  0x5408abf7L,  0x50c9b640L,
    0x4e8ee645L,  0x4a4ffbf2L,  0x470cdd2bL,  0x43cdc09cL,
    0x7b827d21L,  0x7f436096L,  0x7200464fL,  0x76c15bf8L,
    0x68860bfdL,  0x6c47164aL,  0x61043093L,  0x65c52d24L,
    0x119b4be9L,  0x155a565eL,  0x18197087L,  0x1cd86d30L,
    0x029f3d35L,  0x065e2082L,  0x0b1d065bL,  0x0fdc1becL,
    0x3793a651L,  0x3352bbe6L,  0x3e119d3fL,  0x3ad08088L,
    0x2497d08dL,  0x2056cd3aL,  0x2d15ebe3L,  0x29d4f654L,
    0xc5a92679L,  0xc1683bceL,  0xcc2b1d17L,  0xc8ea00a0L,
    0xd6ad50a5L,  0xd26c4d12L,  0xdf2f6bcbL,  0xdbee767cL,
    0xe3a1cbc1L,  0xe760d676L,  0xea23f0afL,  0xeee2ed18L,
    0xf0a5bd1dL,  0xf464a0aaL,  0xf9278673L,  0xfde69bc4L,
    0x89b8fd09L,  0x8d79e0beL,  0x803ac667L,  0x84fbdbd0L,
    0x9abc8bd5L,  0x9e7d9662L,  0x933eb0bbL,  0x97ffad0cL,
    0xafb010b1L,  0xab710d06L,  0xa6322bdfL,  0xa2f33668L,
    0xbcb4666dL,  0xb8757bdaL,  0xb5365d03L,  0xb1f740b4L
```

OBSOLETE

```
};
```

4.5.2 API Definition

- **Use CRC16 arithmetic to implement Flash test**

Name	IEC60730_HardwareCRC16Gen
Parameter	pData: test data address Size: data size
Return	CRC value

Description:

This API implements CRC16 generation by internal hardware CRC generator.

The CCITT CRC16 generator polynomial: 0x1021.

Name	IEC60730_HardwareCRC16Test
Parameter	pData: test data address Size: data size Crc: expected CRC code
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API implements hardware CRC16 test, it can be called at startup procedure to test all code area or test sub blocks CRC32 table periodically when code is running.

Name	IEC60730_SoftwareCRC16Gen
Parameter	pData: test data address Size: data size
Return	CRC value

Description:

This API implements CRC16 generation by software CRC arithmetic. The CRC table enquiry method is used. It provides a reference CRC method that On-chip CRC is implemented in a software way. It may be used in other system with which FM3 MCU communicate.

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Name	IEC60730_SoftwareCRC16Test
Parameter	pData: test data address Size: data size Crc: expected CRC code
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API implements software CRC16 test, this test may be implemented in other system with which FM3 MCU communicate.

- **Use CRC32 arithmetic to implement Flash test**

Name	IEC60730_HardwareCRC32Gen
Parameter	pData: test data address Size: data size
Return	CRC value

Description:

This API implements CRC32 generation by internal hardware CRC generator.

The CRC32 generator polynomial: 0x04C11DB7

Name	IEC60730_HardwareCRC32Test
Parameter	pData: test data address Size: data size Crc: expected CRC code
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API implements hardware CRC32 test, it can be called at startup procedure to test all code area or test sub blocks periodically when code is running.

Name	IEC60730_SoftwareCRC32Gen
Parameter	pData: test data address Size: data size
Return	CRC value

Description:

This API implements CRC32 generation by software CRC arithmetic. The CRC table enquiry method is used. It provides a reference CRC method that On-chip CRC is implemented in a software way. It may be used in other system with which FM3 MCU communicate.

OBSOLETE

Name	IEC60730_SoftwareCRC32Test
Parameter	pData: test data address Size: data size Crc: expected CRC code
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR

Description:

This API implements software CRC32 test, this test may be implemented in other system with which FM3 MCU communicate.

4.6 Variable Memory Test

Variable memory test in FM3 MCU means SRAM test, the SRAM size can be configured according to different product, shown as table 1-1.

4.6.1 Test Description

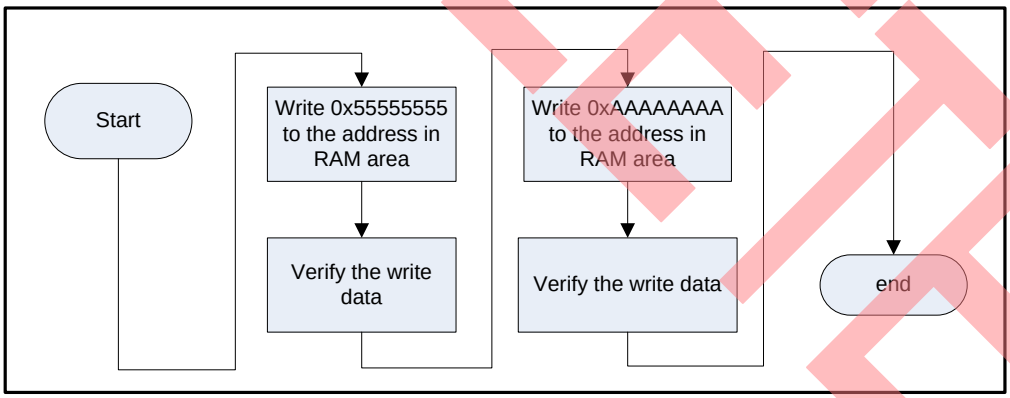
To meet Class B requirement, SRAM test must be checked for "DC fault". A simple checkerboard method is used to implement this SRAM.

This test can be implemented at startup procedure to test entire SRAM area. And it can also test sub blocks periodically when code is running, however user should pay attention that the data will be destroyed after test.

As all RAM area is involved in this test, it is better not to use variable in this test, so assembly is used to implement register test. And as it is highly critical, it is designed that once RAM test error is detected, program will run into an infinite loop.

The procedure to test 1 word data is shown as following figure.

Figure 21. Test 1 Word with Checkerboard Method



OBSOLETE

4.6.2 API Definition

Name	iec60730_ram_test
Parameter	StartAddr(R0): start RAM address EndAddr(R1): end RAM address
Return	None

Description:

This API tests SRAM area with Checkerboard arithmetic which writes alternate “0” and “1” to memory, and verifies if the write data is right by reading back the data written. It can detect stuck-at faults and direct coupling faults.

This test should be called in startup procedure, and it can also be called in cycle, but the data is not saved after test.

4.7 IO Test

FM3 MCU has up to 8 IO ports: Port0-Port8, each port has up to 16 channels. These ports can be configured according to different package.

4.7.1 Test Description

To meet Class B requirement, GPIO must be check for “Function error”. So function test is implemented for both input and output function. The IO direction can be configured by IO register shown in Figure 15.

- Input IO configuration: ADE=0,PFR=0,DDR=0
- Output IO configuration: ADE=0,PFR=0,DDR=1

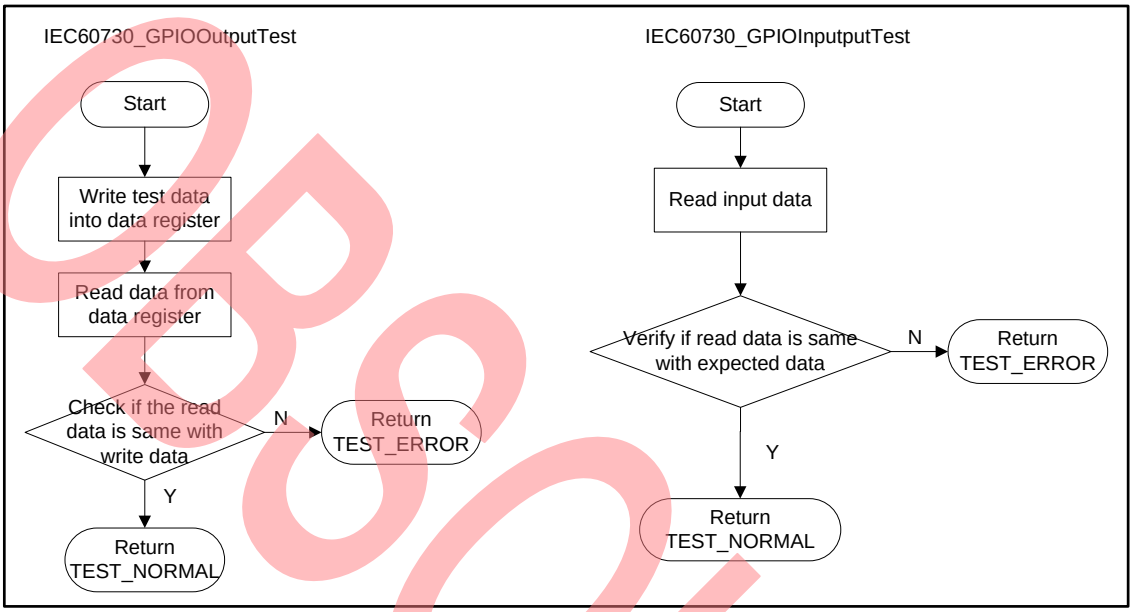
Figure 22. IO Function Configuration

I/O Port Function		ADE/ SPSR	PFR	DDR	PCR	EPFR
Available main function	Available sub function					
Special pin Analog input USB Oscillation	N/A	1	-	-	Disconnect	*0
GPIO function input pin	Peripheral function input pin	0	0	0	Valid	*1
GPIO function output pin	GPIO function input pin (FB) Peripheral function input pin (FB)			1	Disconnect	
Peripheral function output pin	GPIO function input pin (FB) Peripheral function input pin (FB)		1	-	Disconnect	*2
Peripheral function bidirectional pin	GPIO function input pin (FB) Peripheral function input pin (FB)				Valid	*3
Peripheral function input pin	GPIO function input pin				Valid	*4

OBSOLETE

The IO input test checks if selected IO input value which stores in PDIR is same with expected value. And IO output can check if output value by which stores in PDOR is correct. These tests should be tested in startup procedure as function test.

Figure 23. IO Input/Output Test Flowchart



OBSOLETE

4.7.2 API Definition

Name	IEC60730_GPIOOutputTest
Parameter	Port: port number Bit: bit number Value: output level
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR 2: IEC60730_TEST_PARA_ERROR

Description:

This API implements GPIO output test by setting a level for output pin and check if read back value is the expected value.

Name	IEC60730_GPIOInputTest
Parameter	Port: port number Bit: bit number Value: expected pin level
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR 2: IEC60730_TEST_PARA_ERROR

Description:

This API implements GPIO input test by reading the value from input pin and check if read value is the expected value.

4.8 AD Test

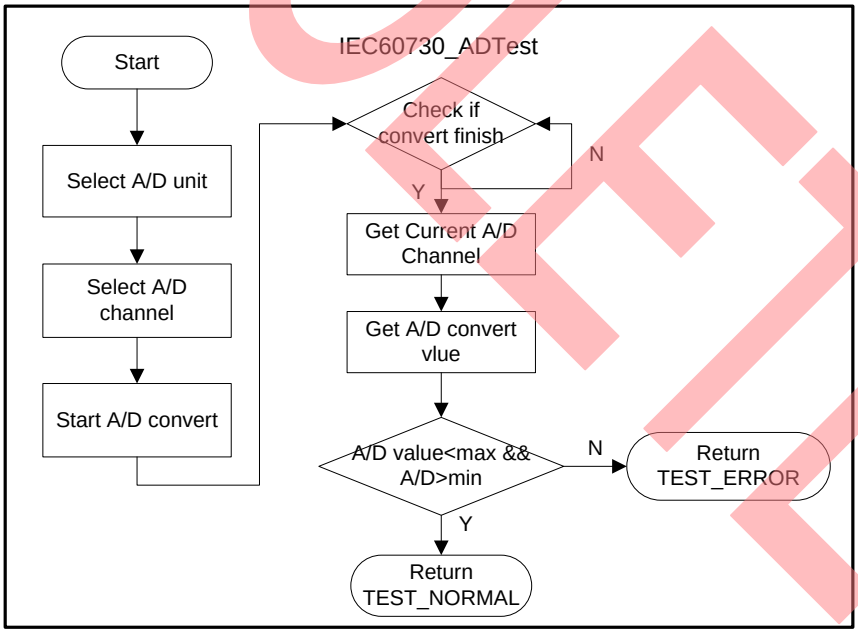
FM3 MCU integrates a 10bit or 12bit AD module. It has 3 units with totally 16 channels.

4.8.1 Test Description

To meet Class B requirement, AD must be check for “Function error”. This test samples AD signal from selected AD channels and check if the AD convert values are in the expected ranges.

Scan mode is used, multi-channel can be tested at the same time. The AD test flowchart shows the flow to check 1 ADC channel.

Figure 24. AD Test Flowchart



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4.8.2 API Definition

Name	IEC60730_ADTest
Parameter	pADCInfo: pointer to ad_test_info_t structure typedef struct ad_test_info { uint8_t ADUnit; /* unit num, 10/12 bit A/D -> 0/1/2 */ uint8_t *Ch; /* pointer to AD channel num */ uint8_t ChSize; /* channel size */ uint16_t *ExpLowerValue; /* pointer to expected lower value */ uint16_t *ExpUpperValue; /* pointer to expected upper value */ } ad_test_info_t;
Return	0: IEC60730_TEST_NORMAL 1: IEC60730_TEST_FUNC_ERROR 2: IEC60730_TEST_PARA_ERROR

Description:

This API implements AD test by checking if AD convert result is in expected range. It should be implemented in startup procedure.

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5 Example Project

Two demo projects are provided according to IAR and keil IDE. This chapter introduces IAR demo project based on IAR MB9BF506R-SK EV-Board (MCU: MB9BF506R) and shows how to integrate the IEC60730 STL into a real system.

5.1 User Configuration

User should first configure some definitions in IEC60730_user.h file.

5.1.1 The definition "MCU_TYPE_MB9BF500"

If MB9BF500 is used, enable the definition "MCU_TYPE_MB9BF500", else disable this definition.

MB9BF506R is used in the IAR MB9BF506R-SK EV-Board, so disable the definition "MCU_TYPE_MB9BF500".

5.1.2 The definition "IEC60730_FLASHTEST_USE_CRC16"

If User wants to use CRC16 arithmetic for Flash test, enable this definition, if user wants to use CRC32 arithmetic for Flash test, disable this definition.

In this demo program, CRC16 arithmetic is used.

5.1.3 The definition "IEC60730_CLKTEST_USE_CSV"

If User wants to use CSV to implement clock test, enable this definition, or clock test will be done with watch counter as standard timer, which is sourced by sub clock.

In the demo program, the latter method is demonstrated.

5.2 Project Structure

Class B STL routines are divided into two main processes: startup and periodic self-tests. The periodic test must be initialized by a set-up block before it is applied.

5.2.1 Startup Self-Test

PC, register, SRAM test are all startup self-tests, and they should be called in reset handler.

And Flash, AD, IO can be tested after system clock initialization after program jumps into main function.

For AD test, channel 13 (Potentiometer input), channel 7, 8, 9 (inertial Sensor input) are used for test.

For IO input test, joystick input pin P30 (LEFT), P31 (RIGHT), P40 (UP), P41 (Down) are used for test.

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5.2.2 Periodic Test Initialization

Interrupt and clock test should be initialized before tests start.

- **Interrupt Test Initialization**

It is designed that a dual time interrupt is used to monitor reload timer 0-3. The initialization setting parameter is shown as following table.

Table 4. IO Input/Output Test Flowchart

Interrupt Name	Interrupt Interval	Interrupt of dual timer	Standard Frequency	Pre-defined Range
Reload timer 0	2.5ms	25ms	10	[8,12]
Reload timer 1	1ms	25ms	25	[22, 28]
Reload timer 2	500us	25ms	50	[45,55]
Reload timer 3	250us	25ms	100	[95,105]

- **Clock Test Initialization**

The CPU clock is HCLK, and the source clock of dual timer in this system is set to PCLK0 (HCLK/2). So the source clock of dual timer can be tested indirectly instead of CPU clock by watch counter.

It is designed that the interrupt Interval of watch counter is 1s and interrupt Interval of dual timer is 25 ms, so the Standard Frequency of dual timer is 40 and the accepted range is set between 45 and 55. Assume it takes 10 cycles to implement main loop. So the minimum execution time of main loop is 1/8000000 s, so set the threshold value to 10000000.

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5.2.3 Periodic Test

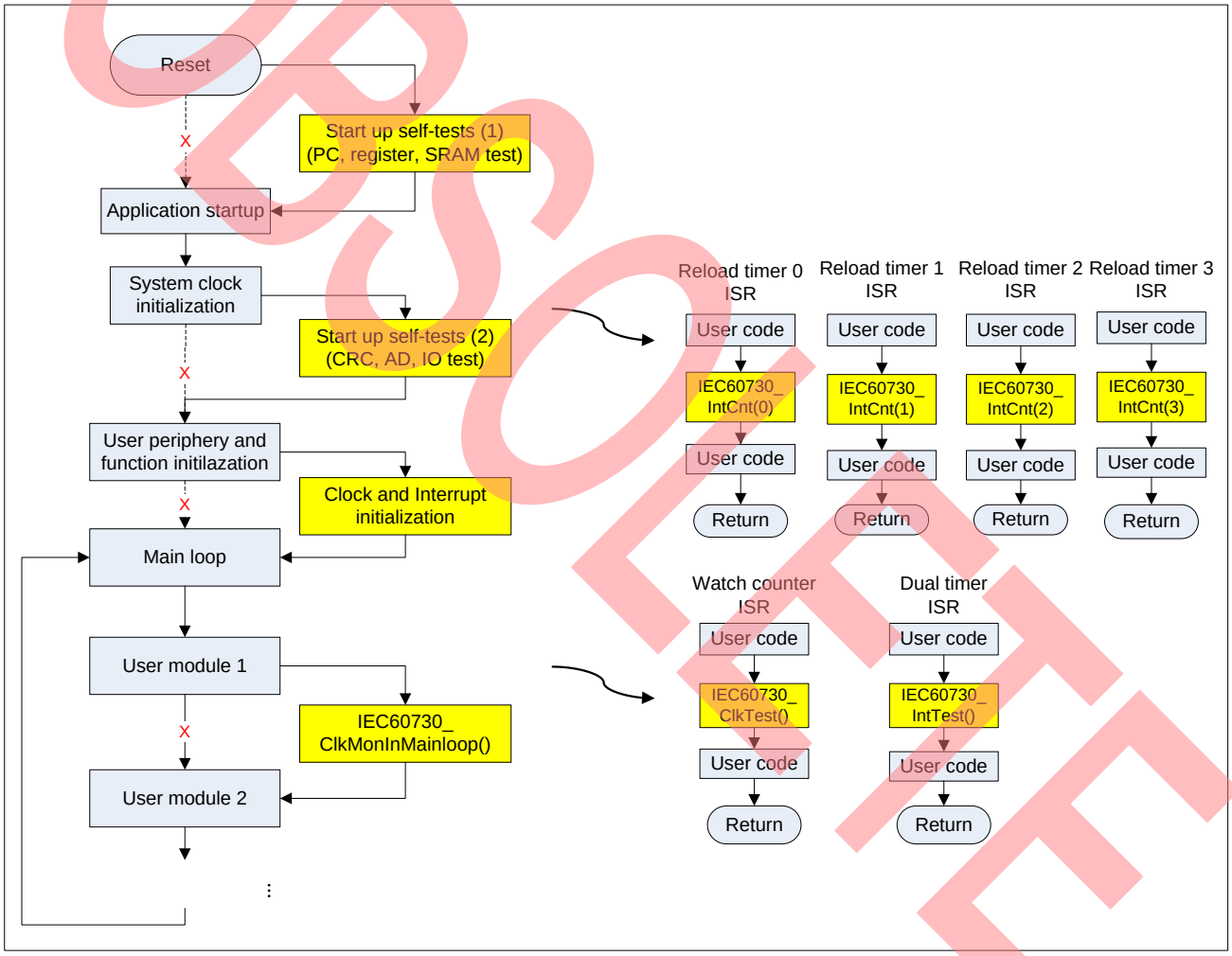
The interrupt and clock test should be tested in period when code is running.

Integrate **IEC60730_IntTest** into dual timer interrupt and **IEC60730_IntCnt** into each reload timer interrupts.

Integrate **IEC60730_ClkTest** into watch counter interrupt, **IEC60730_ClkCnt** into dual timer interrupt, and **IEC60730_ClkMonInMainloop** into main loop.

The Figure 25 shows the basic principle of how to integrate the Class B software package into this application software.

Figure 25. Project Structure



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5.3 Sample Code

5.3.1 Startup File

- **Reset handler**

Figure 26. Reset Handler Sample Code

```
Reset Handler

      bl iec60730_reg_test   ; after reset, test register first
      bl iec60730_pc_test    ; test pc
      ldr r0, =0x20000000     ; set RAM start address
      ldr r1, =0x20007fff     ; set RAM end address
      bl iec60730_ram_test   ; test all Data RAM area
```

5.3.2 Main File

- **Main function**

Figure 27. Main Function Sample Code

```
int32 t main(void)
{
    int32_t cntr = 0;
    uint32_t hw_crc,sw_crc;
    uint8 t bit;
    uint8 t a[10] = {0x00,0x11,0x22,0x33,0x44,0x55,0x66,0x77,0x88,0x99};
    uint8 t ch[4] = {7,8,9,13};  /* ch7: X-axes input */
                                 /* ch8: Y-axes input */
                                 /* ch9: Z-axes input */
                                 /* ch13: VR2 input   */
    /* place board in horizon */
    /*
    * x=0x800
    * y=0x800
    * z=0xb41
    */
    /* move the VR2 at middle */
    /* VR2 value = 0xfff/2 = 0x7ff */
    uint16 t low[16] = {0x700,0x700,0xb00,0x500};
    uint16 t up[16] = {0x900,0x900,0xc00,0xB00};
    ad_test_info_t ADTest_Info = {AD_UNIT0, ch, sizeof(ch)/sizeof(uint8_t), low, up};
    SystemInit();
    /* use hardware CRC16 to calculate expected crc first,
       then verify if the CRC code calculated by software is same with expected crc */
    hw crc = IEC60730 HardwareCRC16Gen(a, sizeof(a));
    if(IEC60730 TEST NORMAL != IEC60730 SoftwareCRC16Test(a, sizeof(a), hw crc)) {while(1);};
    /* use software CRC16 to calculate expected crc first,
       then verify if the CRC code calculated by hardware is same with expected crc */
    sw crc = IEC60730 SoftwareCRC16Gen(a, sizeof(a));
    if(IEC60730 TEST NORMAL != IEC60730 HardwareCRC16Test(a, sizeof(a), sw crc)) {while(1);};
    /* GPIO output test
    *  test P32-P39 (control LED1-LED8)
    */
#ifdef MB9BF506R_SK
    for(bit=BIT NUM 2;bit<BIT NUM 9;bit++)
    {
        if(IEC60730 TEST NORMAL != IEC60730 GPIOOutputTest(PORT NUM 3, bit, TEST PIN LOW)
           || IEC60730_TEST_NORMAL != IEC60730_GPIOOutputTest(PORT_NUM_3, bit, TEST_PIN_HIGH))
        {
            while(1);
        }
```

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```
#endif
    /* GPIO input test
    *  test P30(LEFT)
    *  test P31(RIGHT)
    *  test P40(UP)
    *  test P41(DOWN)
    */
#ifdef MB9BF506R_SK
    if(IEC60730_TEST_NORMAL != IEC60730_GPIOInputTest(PORT_NUM_3, BIT_NUM_0, 1)){while(1);};
    if(IEC60730_TEST_NORMAL != IEC60730_GPIOInputTest(PORT_NUM_3, BIT_NUM_1, 1)){while(1);};
    if(IEC60730_TEST_NORMAL != IEC60730_GPIOInputTest(PORT_NUM_4, BIT_NUM_0, 1)){while(1);};
    if(IEC60730_TEST_NORMAL != IEC60730_GPIOInputTest(PORT_NUM_4, BIT_NUM_1, 1)){while(1);};
#endif
    /* AD test
    *  check if ch7,ch8,ch9,ch13 input is in expected range.
    */
#ifdef MB9BF506R_SK
    if(IEC60730_TEST_NORMAL != IEC60730_ADTest(&ADTest_Info)){while(1);};
#endif
    /*Init LEDs*/
    LED_Init();
    /*Init Buttons*/
    Button_Init();
    /*Init LCD Pins*/
    HD44780_IO_Init();
    /* Interrupt test initialization */

IEC60730_IntTestInit(IntTest_Freq,IntTest_FreqLower,IntTest_FreqUpper,IntTest_FreqInit,sizeof(IntTest_Fr
eq)/sizeof(uint32_t));
   /* clock test initialization
    *  test CPU clock by checking if the 25ms interval time is set for dual timer,
    *  the occurance frequency of dual times is about 40 in a 1s interval(produced by watch counter)
    *  1 machine cycle = (1/80Mhz)=0.0125us, assume it takes 10 cycles(actually much more) to implement
main loop,
    *  threshold value should be more than (1/(0.0125u*10)= 8000000)
    */
    IEC60730_ClkInit(35,45,10000000);
    /* init watch conter */
    WTC_Init();
    /* init dual timer */
    DT_Init();
    /* init 4 base timers */
    BT_Init();
#ifdef MB9BF506R_SK
    /*Power up LCD*/
    if(HD44780_OK != HD44780_PowerUpInit())
    {
        return 1;
    }
    /* LCD diplay */
    HD44780_StrShow(1,1,(const HD44780_STRING_DEF *)"IEC60730 Class B");
    HD44780_StrShow(3,2,(const HD44780_STRING_DEF *)"Self-Test Lib");
#endif
    /*Main Loop*/
    while(1)
    { /*Wait for timer tick*/
        if(Tmr1Tick)
        { /*Clear timer tick flag*/
            Tmr1Tick = 0;
            /*update counter*/
            cntr--;
            /*leds update*/
            LED_PDOR &= ~LED_MASK;
            LED_PDOR |= ((cntr) & LED_MASK);
        }
        if(IEC60730_TEST_NORMAL != IEC60730_ClkMonInMainloop())   /* monitor watch counter
        {
```

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```
            while(1);
        }
    }
```

- **Dual Timer ISR**

Figure 28. Dual Timer ISR

```
void DT QDU IRQHandler(void)
{
    Tmr1Tick = 1;
    FM3_DTIM->TIMER1INTCLR= 1;
    /* count the clock tick */
    IEC60730 ClkCnt();
    /* implemenmt interrupt test */
    if(IEC60730_TEST_NORMAL != IEC60730_IntTest())
    {
        while(1);
    }
}
```

- **Watch Counter ISR**

Figure 29. Watch Counter ISR

```
void CLK_IRQHandler(void)
{
    if(bFM3_INTREQ_IRQ24MON_WCINT)
    {
        FM3_WC->WCCR &= 0xFE;    /* Clear interrupt flag */
        /* implement clock test */
        if(IEC60730_TEST_NORMAL != IEC60730_ClkTest())
        {
            while(1);
        }
    }
}
```

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- **Reload Timer ISR**

Figure 30. Reload Timer ISR

```
void BTIM IRQHandler(void)
{
    if(FM3_BT0_RT->STC&0x01)
    {
        FM3_BT0_RT->STC = FM3_BT0_RT->STC & 0xFE;
        IEC60730_IntCntPro(0);              /* count frequence value for interrupt 0 */
    }
    else if(FM3_BT1_RT->STC&0x01)
    {
        FM3_BT1_RT->STC = FM3_BT1_RT->STC & 0xFE;
        IEC60730_IntCntPro(1);              /* count frequence value for interrupt 1 */
    }
    else if(FM3_BT2_RT->STC&0x01)
    {
        FM3_BT2_RT->STC = FM3_BT2_RT->STC & 0xFE;
        IEC60730_IntCntPro(2);              /* count frequence value for interrupt 2 */
    }
    else if(FM3_BT3_RT->STC&0x01)
    {
        FM3_BT3_RT->STC = FM3_BT3_RT->STC & 0xFE;
        IEC60730_IntCntPro(3);              /* count frequence value for interrupt 3 */
    }
}
```

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6 STL API Performance

Figure 31. STL API Performance

API Name	Execution time (Cycles)	Stack usage (Bytes)	ROM Usage (Bytes)	RAM usage (Bytes) (Global variable)
iec60730_pc_test	158	0	136	0
iec60730_reg_test	498	0	642	0
IEC60730_IntTestInit	191 (4 interrupts)	8	58	0
IEC60730_IntCntPro	47	0	36	0
IEC60730_IntTest	339 (4 interrupt)	0	74	20
IEC60730_ClkCnt	54	0	32	0
IEC60730_ClkTest	92	0	80	29
IEC60730_ClkMonInMainloop	79	8	68	0
IEC60730_ClkTestReset	60	0	30	0
IEC60730_InitCSV	280	8	224	0
IEC60730_CheckCSVStat	30	0	56	0
IEC60730_HardwareCRC16Gen	320 (10 bytes data)	4	98	0
IEC60730_HardwareCRC16Test	348 (10 bytes data)	8	20	0
IEC60730_SoftwareCRC16Gen	326 (10 bytes data)	4	52+ 512 (CRC table)	0
IEC60730_SoftwareCRC16Test	354 (10 bytes data)	8	22	0
IEC60730_HardwareCRC32Gen	320 (10 bytes data)	4	92	0
IEC60730_HardwareCRC32Test	348 (10 bytes data)	8	20	0
IEC60730_SoftwareCRC32Gen	244 (10 bytes data)	4	42+ 1024 (CRC table)	0
IEC60730_SoftwareCRC32Test	266 (10 bytes data)	8	22	0
iec60730_ram_test	262 (16 bytes data)	0	84	0
IEC60730_GPIOOutputTest	264	24	254	0

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API Name	Execution time (Cycles)	Stack usage (Bytes)	ROM Usage (Bytes)	RAM usage (Bytes) (Global variable)
IEC60730_GPIOInputTest	265	28	266	0
IEC60730_ADTest	2628 (4 channels)	104	1224	0

Notes:

1. The code execution cycle is tested in normal run status.
2. The ROM size of this STL is 3668 bytes. (Use CRC16 for Flash test, and watch counter for clock test)

7 Reference Documents

[1]. IEC 60730-1 Reference Manual Edition3.2, 2007

[2]. Cortex-M3 r2p0 Technical Reference Manual, 2008

[3]. ARMv7-M Architecture Application Level Reference Manual, 2008

[4]. MB9BF500N-DS706-00010-0v01-E (MB9B500 Data Sheet)

[5]. MB9Bxxx-MN706-00002-1v0-E (MB9Axxx/MB9Bxxx Series Periphery Manual)

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Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	-	CHZH	03/18/2011	Original version
			06/08/2011	Add CSV to test clock Add CRC32 in Flash test
			09/01/2011	Port example project on updated hardware platform.
*A	5228238	HUAL	01/11/2017	Migrated Spansion document “MCU-AN-510002-E-12” to Cypress format. Document Obsoleted.

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